

## Group to set guidelines for transfer of optical data

Recognizing that existing computer data transfer formalisms such as IGES were not suitable for optical

data transfer, the International Standards Organization (ISO) set up a task group late last year to develop

standards related to the digital transfer of optical data.

At its first meeting last October, the group agreed to:

- Develop a general philosophy and specification for the standard;
- Define the data record types (surfaces, coatings, etc.);
- Define individual data records;
- Verify these definitions by polling representatives of companies participating in the effort; and
- Write the standard.

The task group's activities should be of particular interest to lens and opto-mechanical designers because the principle area of concern is the transfer of data between lens design programs and CAD/CAM programs. The problem will also arise in the computer integrated manufacture (CIM) of optical components.

More information on this standards writing effort is available from Timothy D. Wise, Santa Barbara Research Center, 75 Coromar Dr., Goleta, Calif. 93117. Wise is the U.S. delegate to the task group.

This work on setting standards for the digital transfer of optical data was among the topics covered at the seventh international meeting of ISO/TC 172 SC 1 held Nov. 8–11, 1988 in Monterey, Calif. ISO/TC 172 is the technical committee dealing with optics and optical instruments; Subcommittee 1 handles fundamental optical standards with working groups focusing on optical testing, optical drawing standards, and environmental testing.

The November session was the first ever held in the United States; previous meetings have taken place in the Federal Republic of Germany and in Switzerland. Twenty-nine delegates from eight countries attended the meeting, which was chaired by Hermann Walter of Rodenstock in Munich and supported by OSA and SPIE. U.S. delegates included Donald Janeczko and Rudolph Hartmann of Martin Marietta Aerospace in Orlando and Robert E. Parks of the University of Arizona. SPIE President Harold E. Bennett of the Naval Weapons Center was a guest participant.

—Robert E. Parks

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